Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/817,273	NISHI, TAKASHI
Examiner	Art Unit
Paul D. Kim	3729

	SEARCHER						
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Class	Subclass	Date	Examiner				
29	606,602.1 846 847	1/9/2006	PK				
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	DATE	EXMR
Reviewed Parent Application 09/914542 (US PAT. 6,725,528)	1/6/2006	PK
Text Search EAST/ NPL (IEEE)	1/9/2006	PK
Updated Text Search EAST/ PGPub	5/2/2006	PK